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In re Patent Application of	:	**Docket No.: YOR920030403US1**
Chandramouli Visweswariah	:	**Group Art Unit:**
Serial No.: To be Assigned	:	**Examiner:**
Filed: Herewith	:	**Date: September 19, 2003**

For: SYSTEM AND METHOD FOR STATISTICAL TIMING ANALYSIS OF DIGITAL CIRCUITS

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Box Patent Application
Washington, D.C. 20231

Sir:

Pursuant to 37 C.F.R. §§ 1.56, 1.97 and 1.98, Applicants' attorney wishes to bring to the attention of the Patent and Trademark Office the document listed on the accompanying form PTO-1449. A copy of the listed document is enclosed. It is respectfully requested that the Examiner consider the cited document and return an initialed copy of the form PTO-1449.

The filing of this Information Disclosure Statement shall not be construed as a representation that a search has been made, or as an admission that the information cited is considered to be material to patentability, or as a representation that no other material information exists.

Respectfully submitted,
Attorney for the Applicant(s)

by _____
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FORM PTO-1449 (Modified) LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	ATTY. DOCKET NO. : YOR920030403US1	SERIAL NO.: CONFIRMATION NO.
	APPLICANT: Chandramouli Visweswariah	
(Use several sheets if necessary)	FILING DATE: HEREWITH	GROUP:

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPRO.)
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AH							

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.)

	AI	Statistical Timing of Parametric Yield Prediction of Digital Integrated Circuits, by J.A.G. Jess, K. Kalafala, S.R. Naidu, R.H.J.M. Otten, C. Visweswariah, pp. 932-937, Design Automation Conference 2003
	AJ	Fast Statistical Timing Analysis By Probabilistic Event Propagation, by Jing-Jia Liou, Kwang-Ting Cheng, Sandip Kundu, and Angela Krstic, pp. 661-666, Design Automation Conference 2001
	AK	Explicit Computation of Performance as a Function of Process Variation by Lou Scheffer, TAU '02, pp. 1-8
	AL	Timing Yield Estimation from Static Timing Analysis, by Anne Gattiker, Sani Nassif, Rashmi Dinakar, and Chris Long, pp. 437-442, International Symposium on Quality Electronic Design, 2001.
	AM	J. A. G. Jess and C. Visweswariah, "System and method for statistical modeling and statistical analysis of integrated circuits," U.S. Patent Application number 01/184,329 filed with the U.S. Patent Office on June 27, 2002.

EXAMINER	DATE CONSIDERED

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.